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Application Number	10709362
Filing Date	2004-04-29
First Named Inventor	David J. HATHAWAY et al.
Art Unit	2863
Examiner Name	T. M. Le
Attorney Docket Number	P27064

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"Statistical Timing for Parametric Yield Prediction of Digital Integrated Circuits", J. A. G. Jess et al., pages 932-937

2003



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